

Abstract Submitted
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Scanning Tunneling Microscopy of the Topological Insulator $\text{Bi}_2\text{Se}_3\text{As}_x$ TESS WILLIAMS, ANJAN SOUMYANARAYANAN, Harvard University, DILLON GARDNER, SHAOYAN CHU, YOUNG LEE, Massachusetts Institute of Technology, JENNIFER E. HOFFMAN, Harvard University — We use a low temperature scanning tunneling microscope to study the topological insulator $\text{Bi}_2\text{Se}_3\text{As}_x$. We present atomic resolution topographies displaying three-fold symmetric impurities. We identify features in the density of states.

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